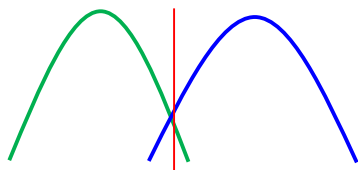


# Using Machine Learning Techniques To Reduce SSD Costs

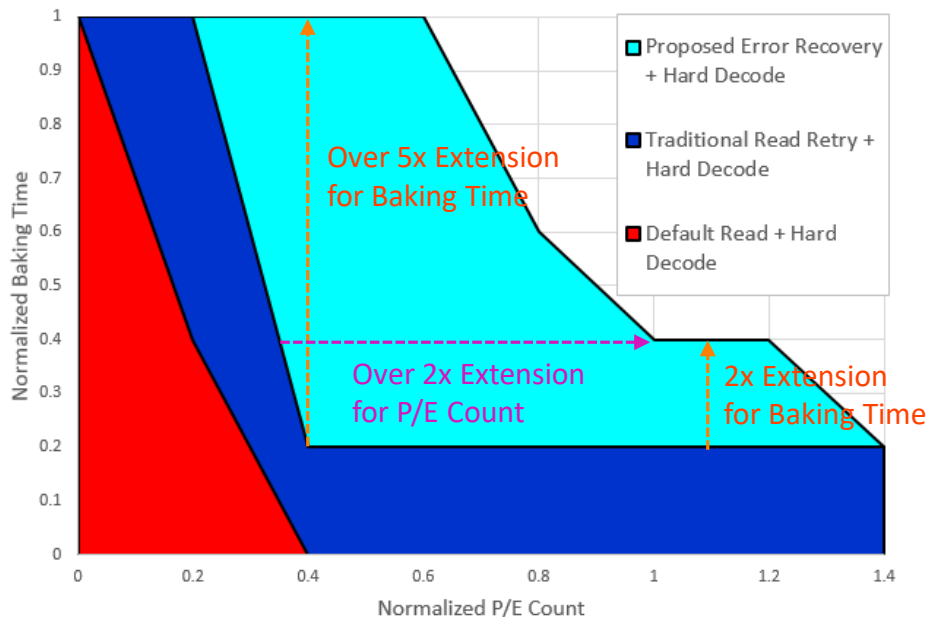
Cloud Zeng  
**LITEON/Storage/NVM Lab**

# eTLC Endurance Improvement

Decoding Coverage/Endurance Comparison



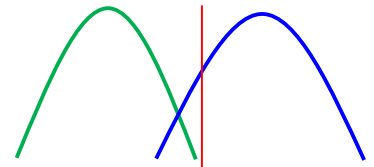
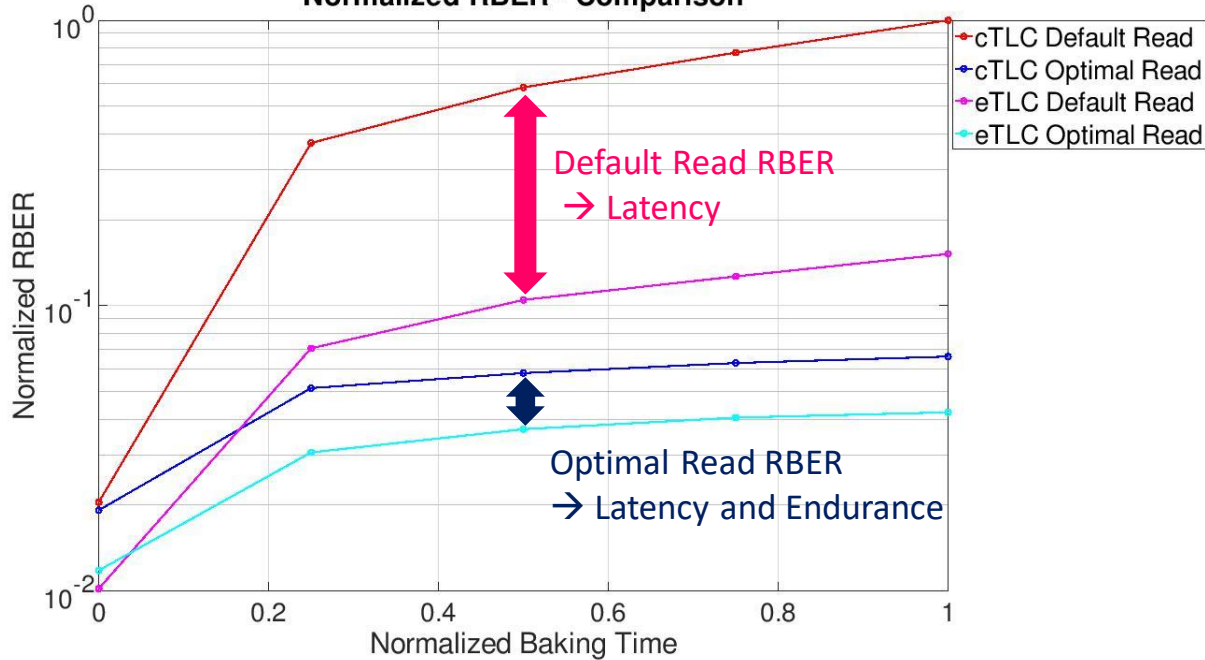
Optimal Read Level  
with Hard Decoding



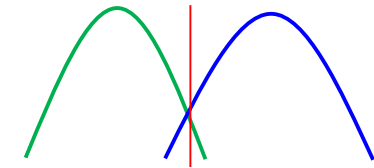
- Our Error Recovery Scheme use ML to find Optimal Parameters for variant operation conditions ( **combination of {PE, DR, RD, Temperature}** )
- **5x** Extension for Baking Time & **2x** Extension for P/E Count

# cTLC vs eTLC – RBER – HTDR

High Temperature Data Retention  
Normalized RBER - Comparison



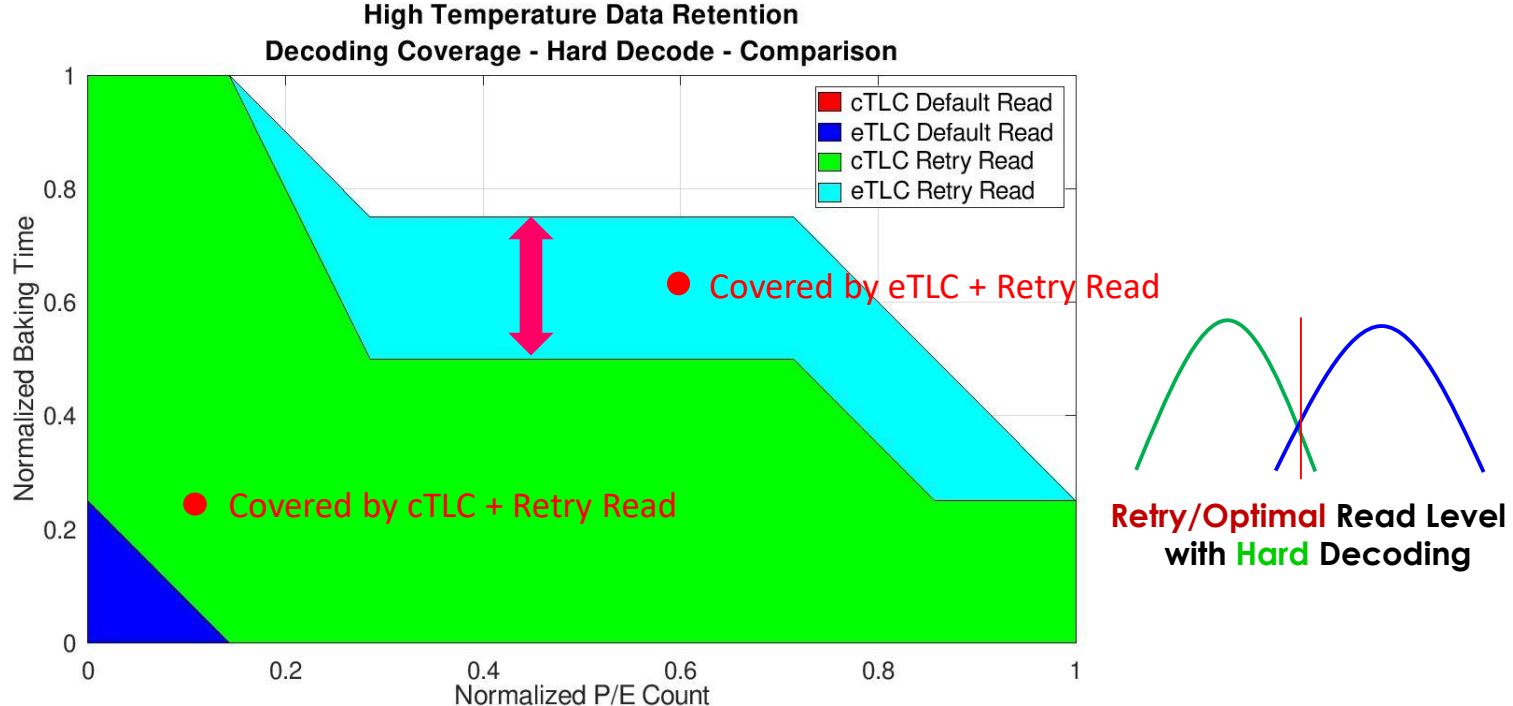
**Default Read Level**



**Optimal Read Level**

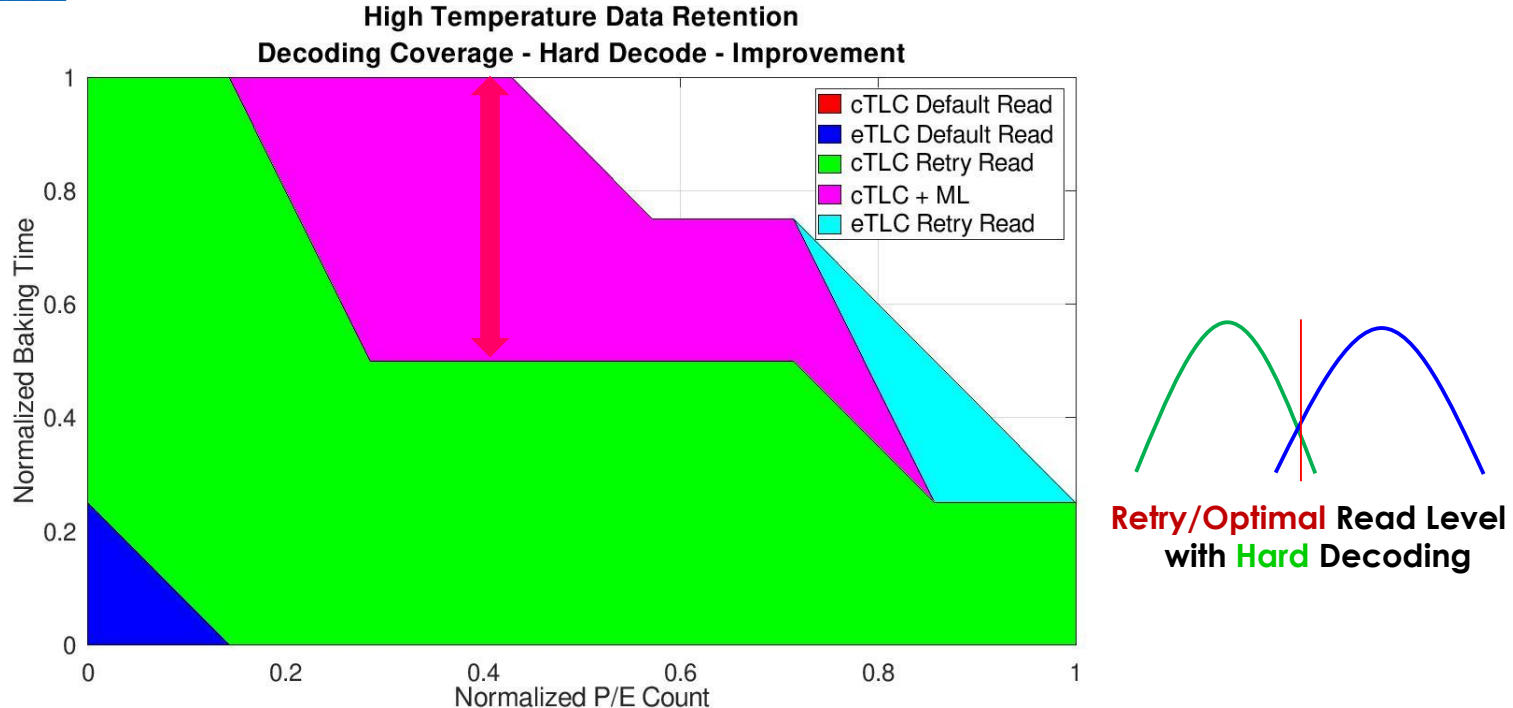
- RBER change with operation condition {P/E, DR, RD, Cross Temp....}
- There is always a RBER gap between cTLC and eTLC

# cTLC vs eTLC – Endurance – HTDR



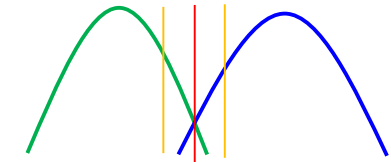
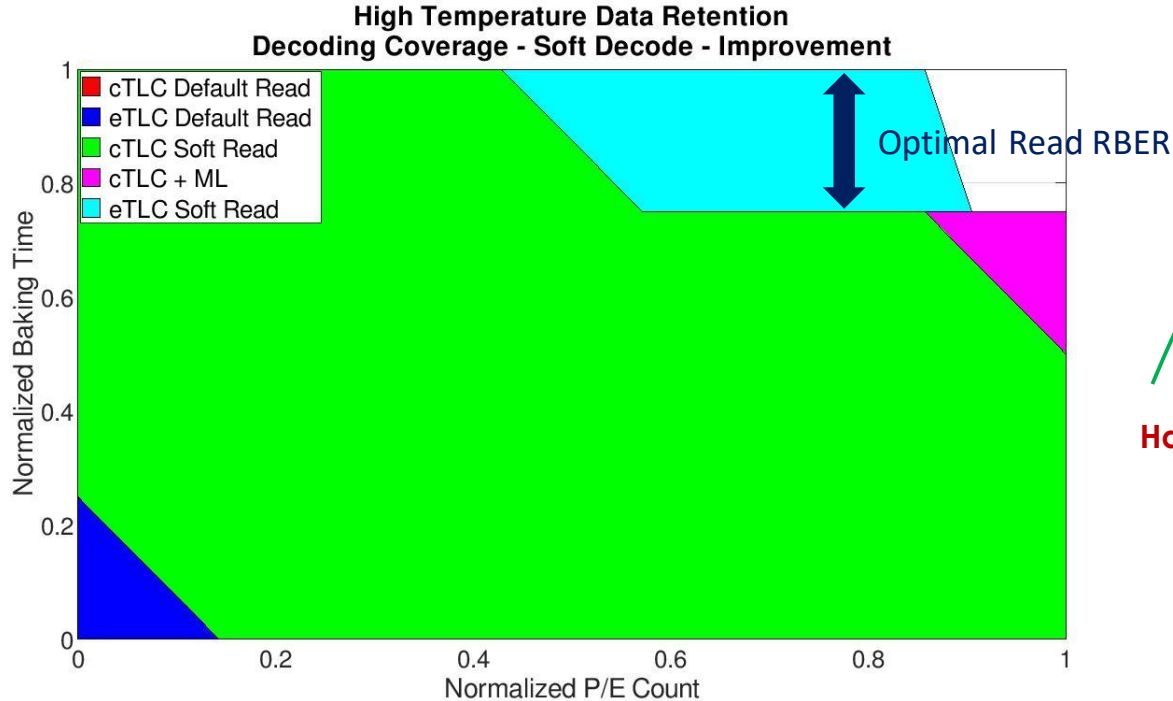
- There is always an endurance gap between cTLC and eTLC
- eTLC with Retry Read has better decoding coverage

# cTLC vs eTLC – Endurance – HTDR



- Our ML techniques can extend decoding coverage for cTLC (Optimized Retry Sequence and Read Level Prediction Model)

# cTLC vs eTLC – Endurance – HTDR

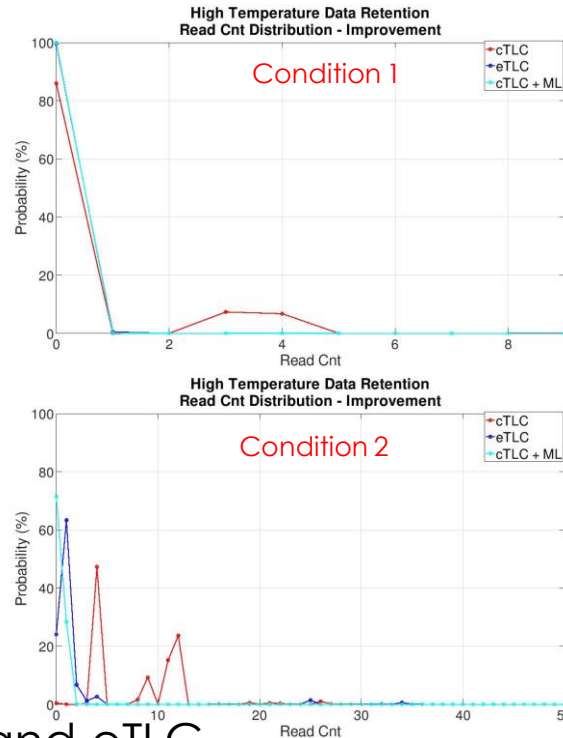
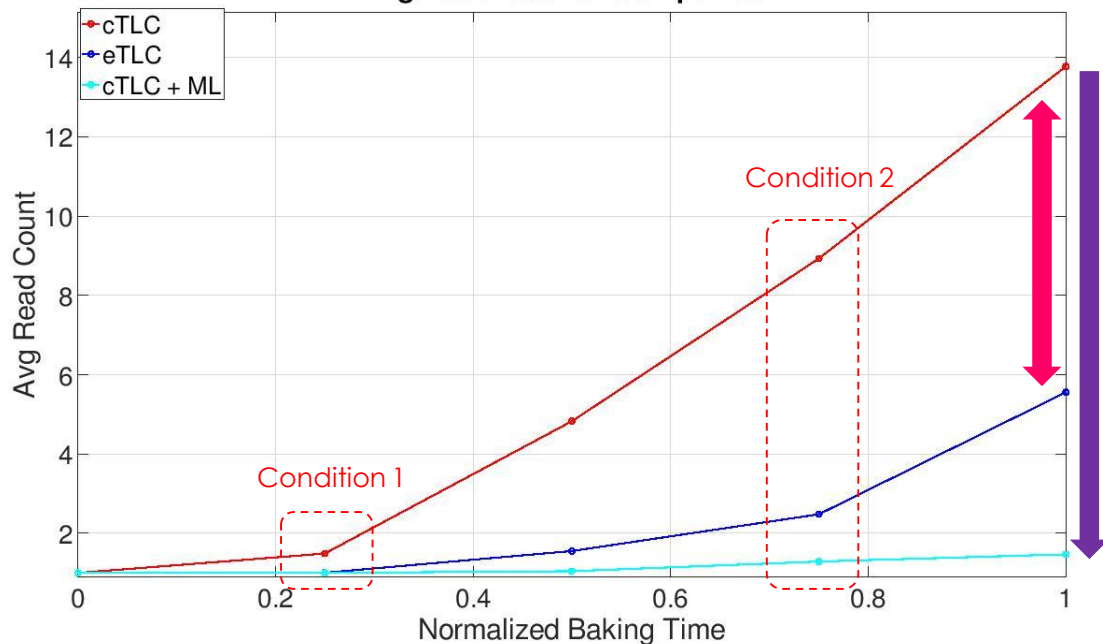


Hard/Soft Read Level  
with Soft Decoding

- There is an intrinsic gap for soft decoding coverage
- The soft decoding coverage is far beyond the spec

# cTLC vs eTLC – Latency – HTDR

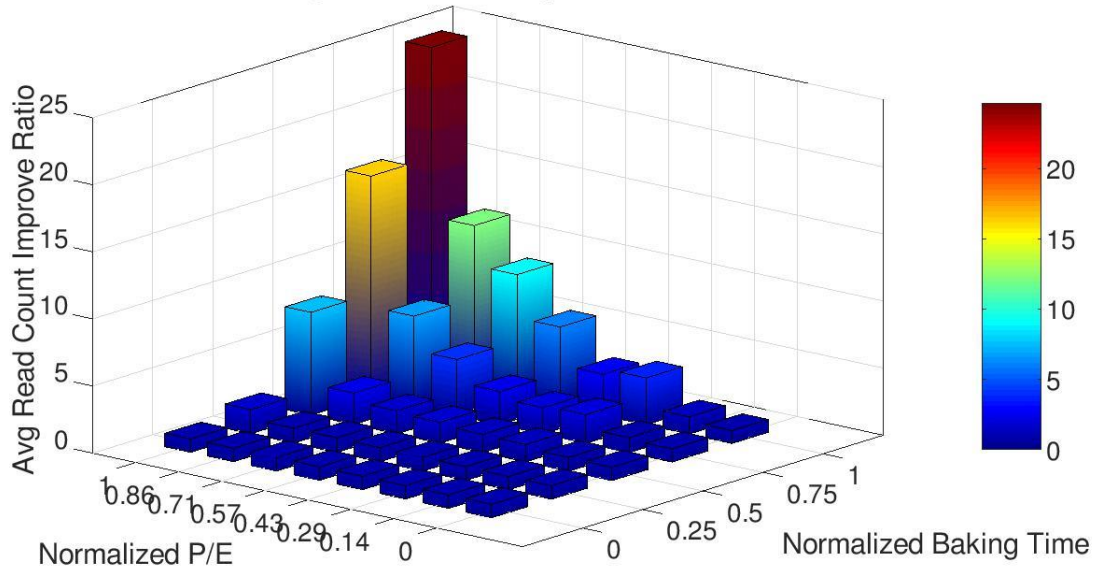
High Temperature Data Retention  
Avg Read Count - Comparison



- There is always a latency gap between cTLC and eTLC
- cTLC + ML can greatly reduce the read latency

# cTLC vs eTLC – Latency – HTDR

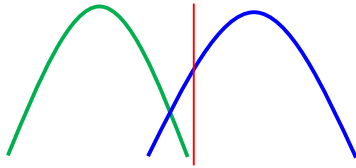
High Temperature Data Retention  
Avg Read Count Improve Ratio



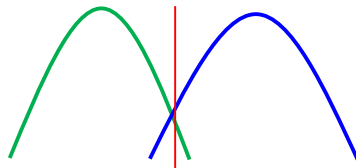
- Improvement Ratio :  $\text{Avg Read eTLC} / \text{Avg Read (cTLC + ML)}$
- cTLC + ML always has less read count compared with eTLC



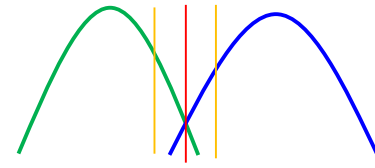
# Error Recovery Flow



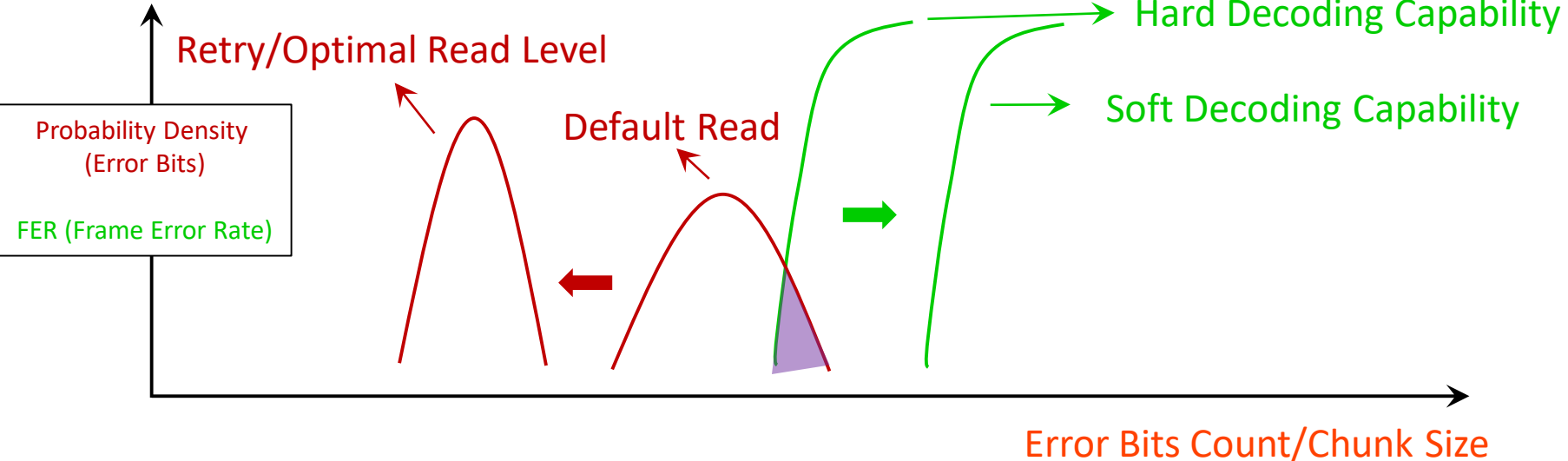
1. **Default** Read Level with **Hard** Decoding



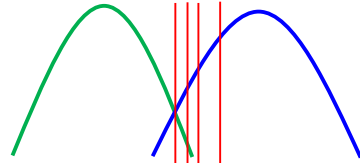
2. **Retry/Optimal** Read Level with **Hard** Decoding



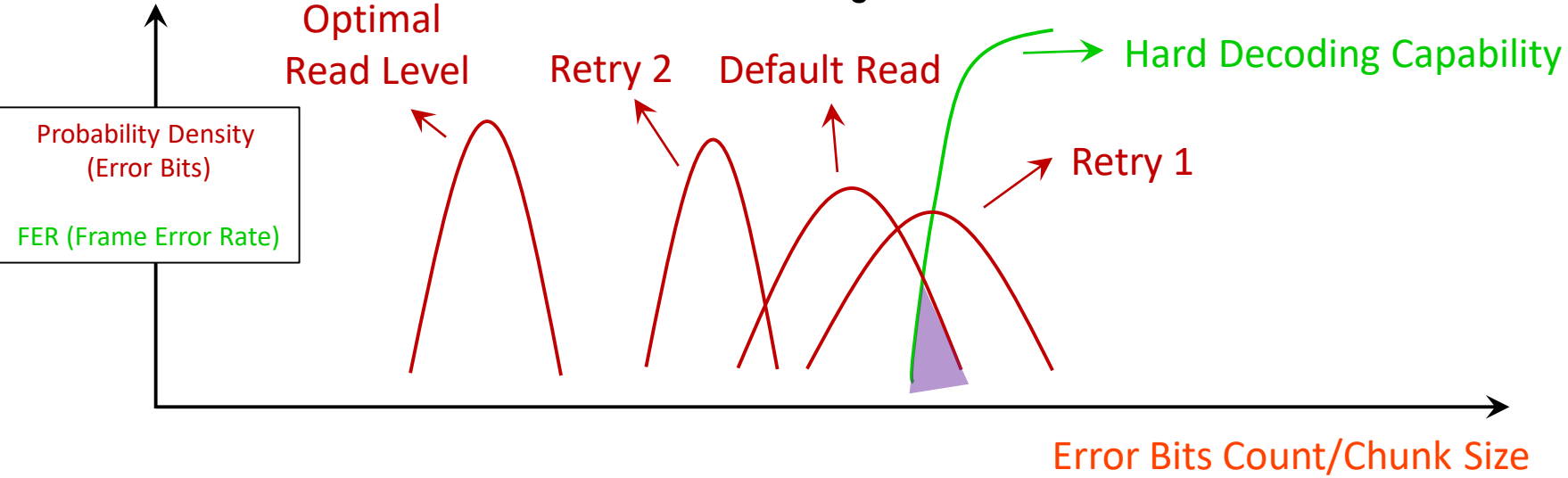
3. **Retry/Optimal** Read Level with **Soft** Decoding



# Read Level Management



1. Optimized Retry Sequence
2. Adjust Default Read Level
3. Accurate Optimal Read Level

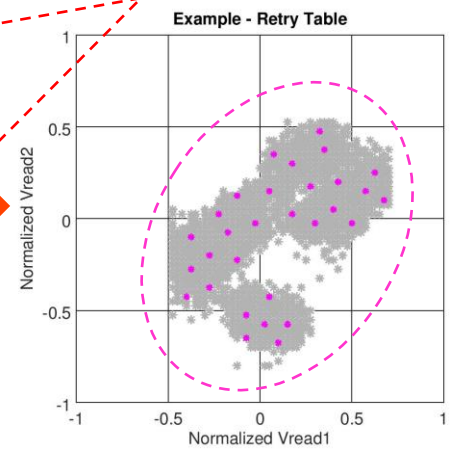
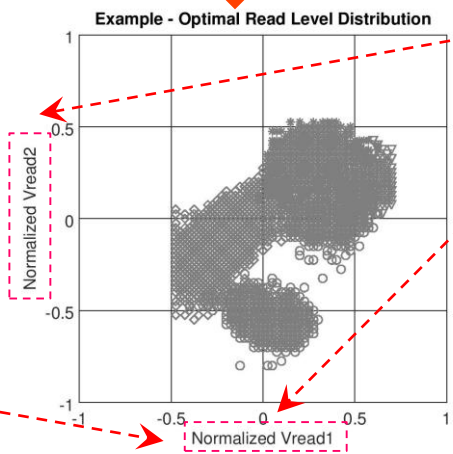
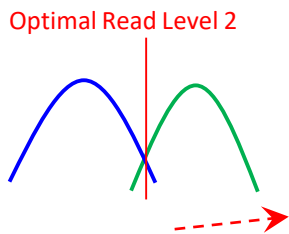
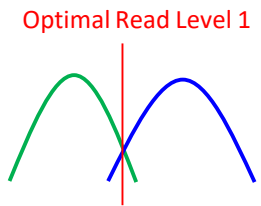


# Read Retry Table – Clustering

Billions of ECC Chunks Info were collected over dice under different failure mode

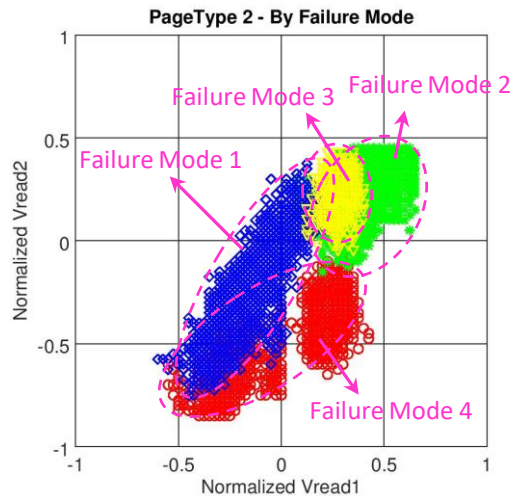
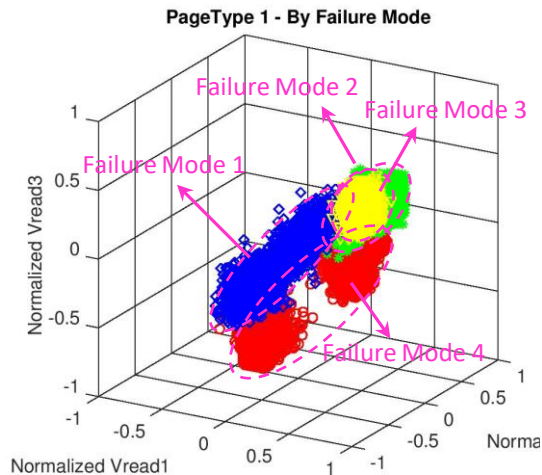
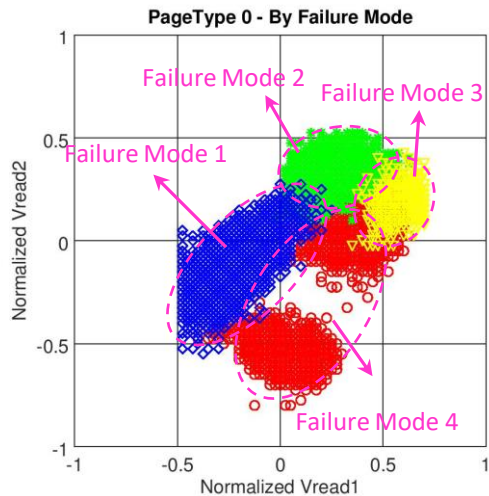
ECC Chunks Info

Die	Plane	BLK	WL	PageType	P/E Count	Baking Time	Optimal Read LV1	Optimal Read LV2
2	0	100	64	0	3000	24	+10	-6
2	1	101	78	0	4000	24	+7	+9
3	1	120	31	0	4000	36	+3	-12
...								



# Optimized Retry Sequence

Find some indexes to separate the data, reduce number of retry tables

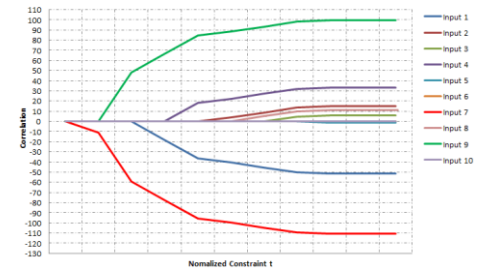


# Prediction Model – Optimal Read Level

## Example: Data Collection

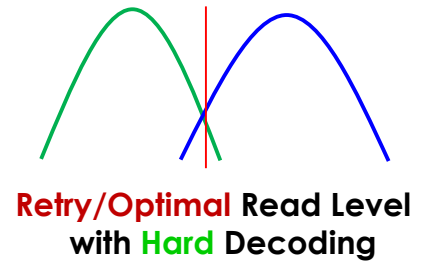
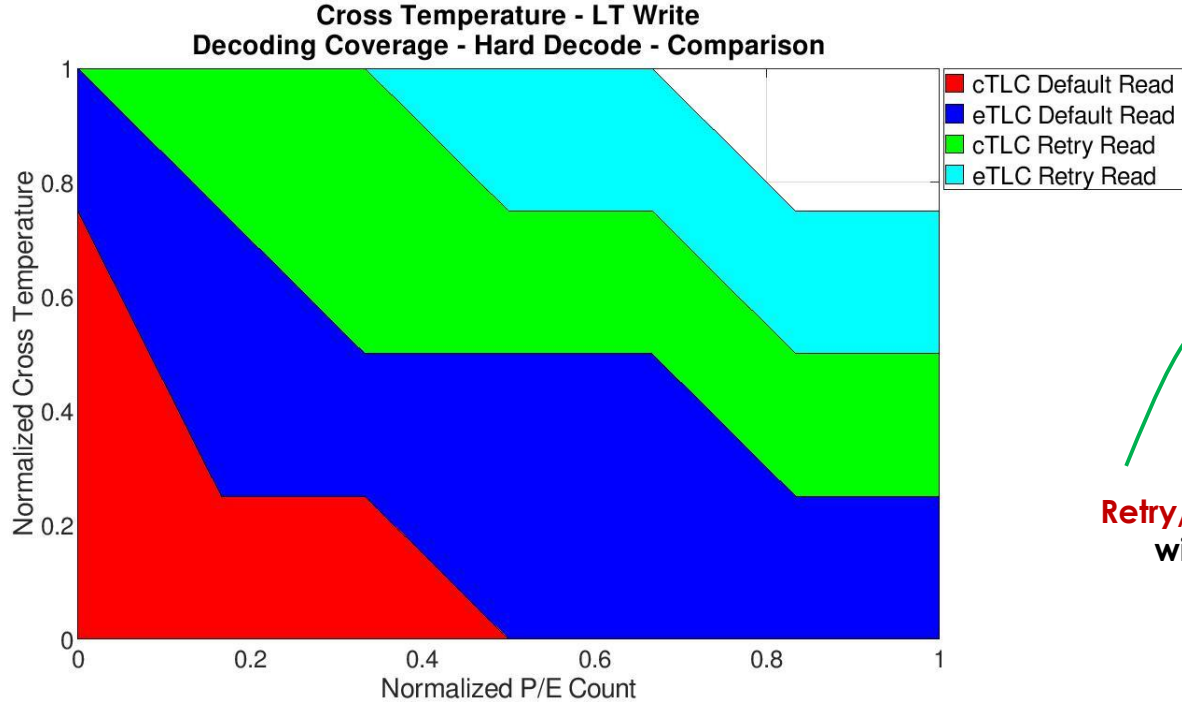
	Input Para 1	Input Para 2	Input Para 3	Input Para 4	Input Para 5	Input Para 6	Optimal HD Read Level
Data 1	1100	589	1794	6322	1000	1000	6
Data 2	932	908	1503	7849	500	500	-5
...	...	...	...	...	...	...	...
Data N	990	842	1894	5692	300	400	3

## Feature Selection



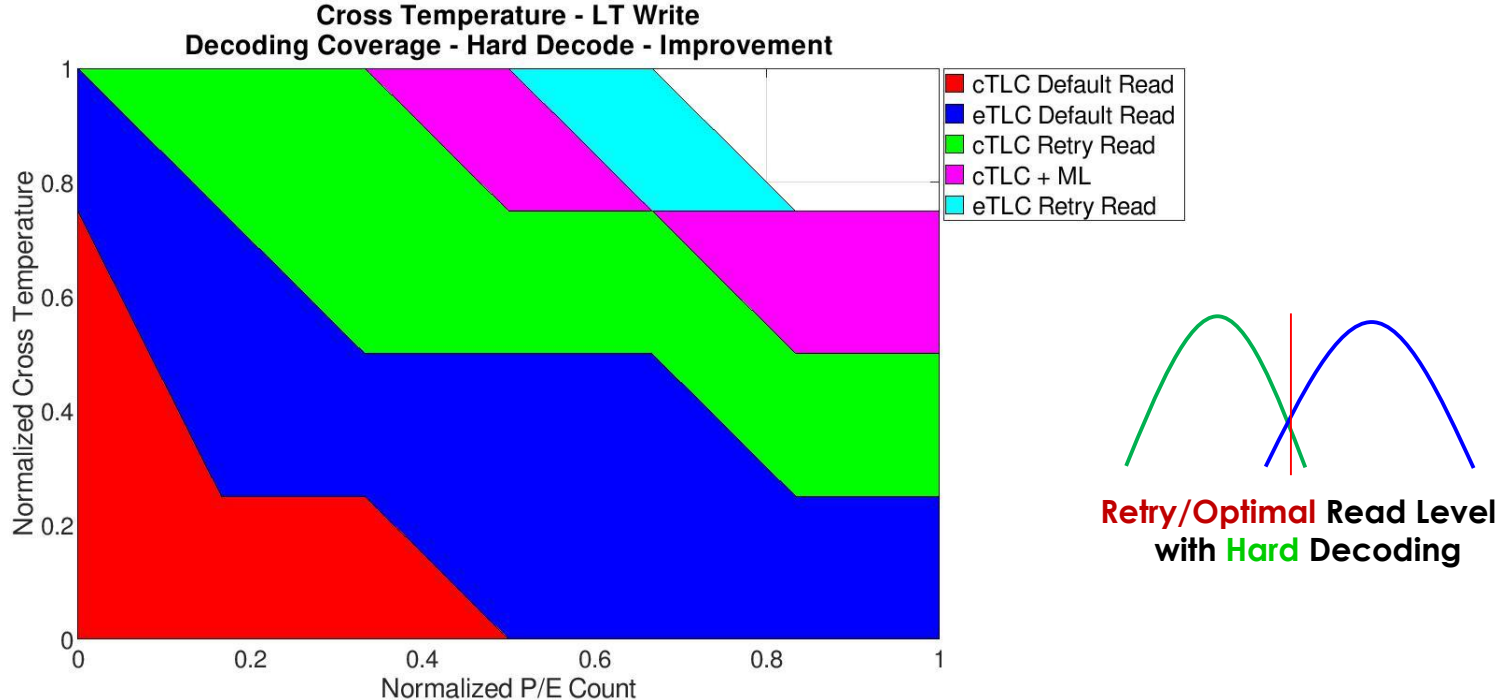
- **What's the Optimal HD Read Level after n Days/Weeks?**
- **Input Parameters:**
  - P/E Cycle, Retention Time, Read Count, Temperature, Dwell ... Program/Erase Time, Histogram ....
- **Regression Problem:**
  - Ordinary Least Square (OLS) Regression
  - Ridge Regression (Hoerl and Kennard, 1970)
  - Other Regression Analysis can be used to solve this problem

# cTLC vs eTLC – Endurance – Cross Temp



- Typical Result : eTLC > cTLC , Retry Read > Default Read

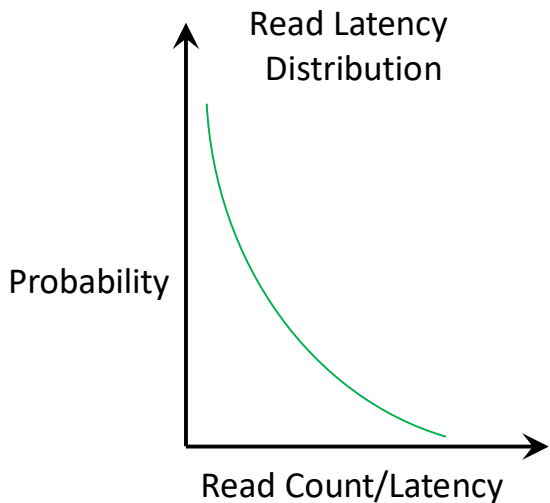
# cTLC vs eTLC – Endurance – Cross Temp



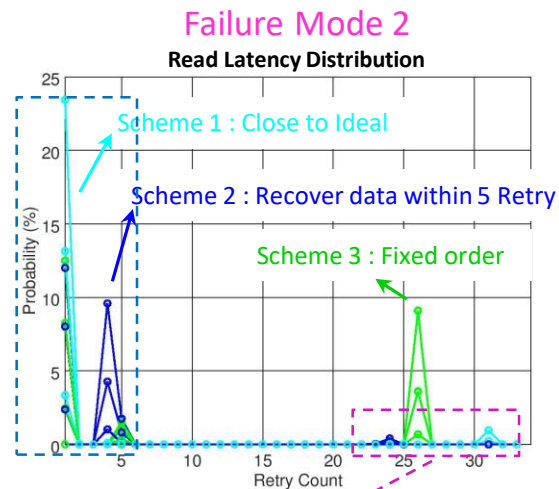
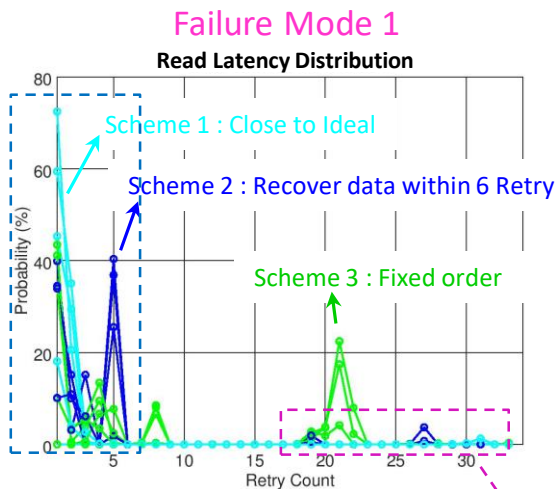
- Our ML techniques can extend decoding coverage for cTLC (Optimized Retry Sequence and Read Level Prediction Model)

# Latency Improvement

**Change Read Level and the Priority of Retry Table dynamically**



**Ideal : monotonically decreasing**



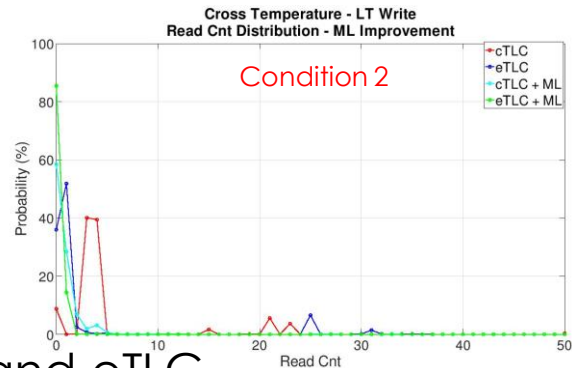
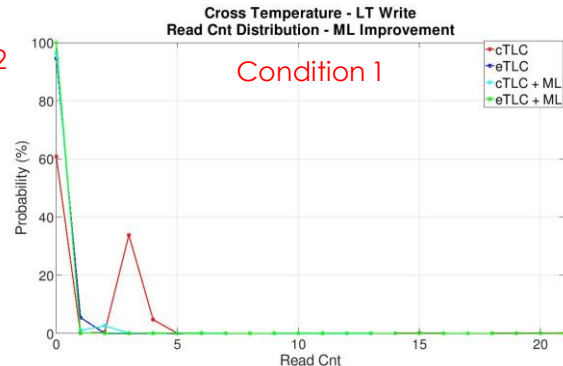
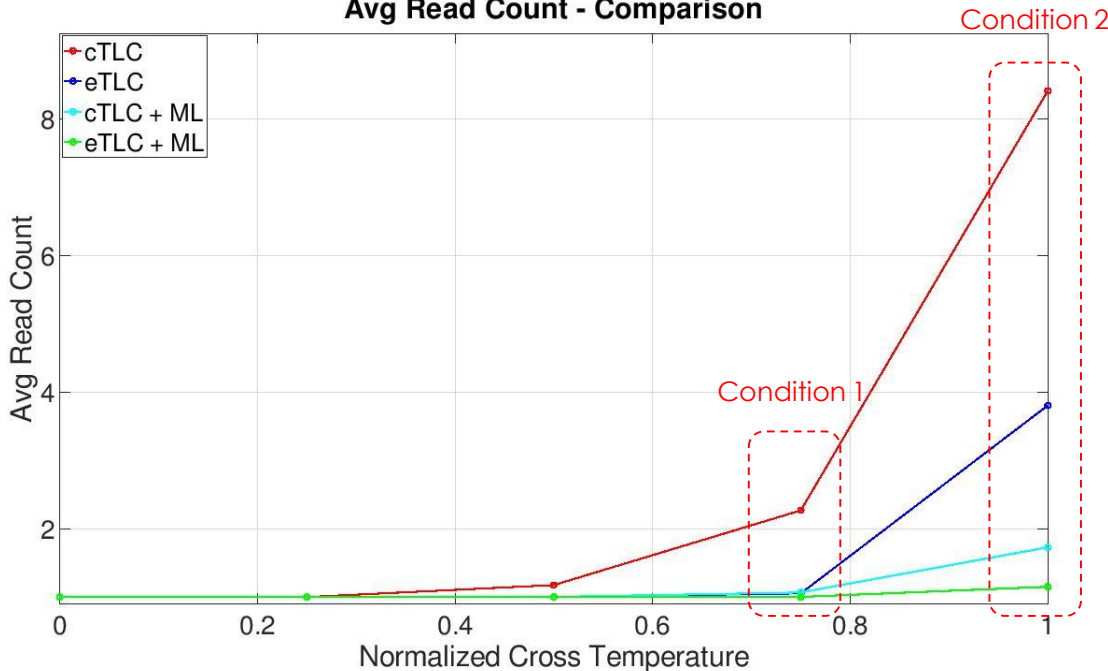
1. Arranged Optimized Retry Sequence + Read Level Adjustment
2. Optimized Retry Sequence (Fixed Order)
3. Traditional Retry Table (Fixed Order)

Last line of defense → Prediction Model : Optimal Read Level/LLR



# cTLC vs eTLC – Latency – Cross Temp

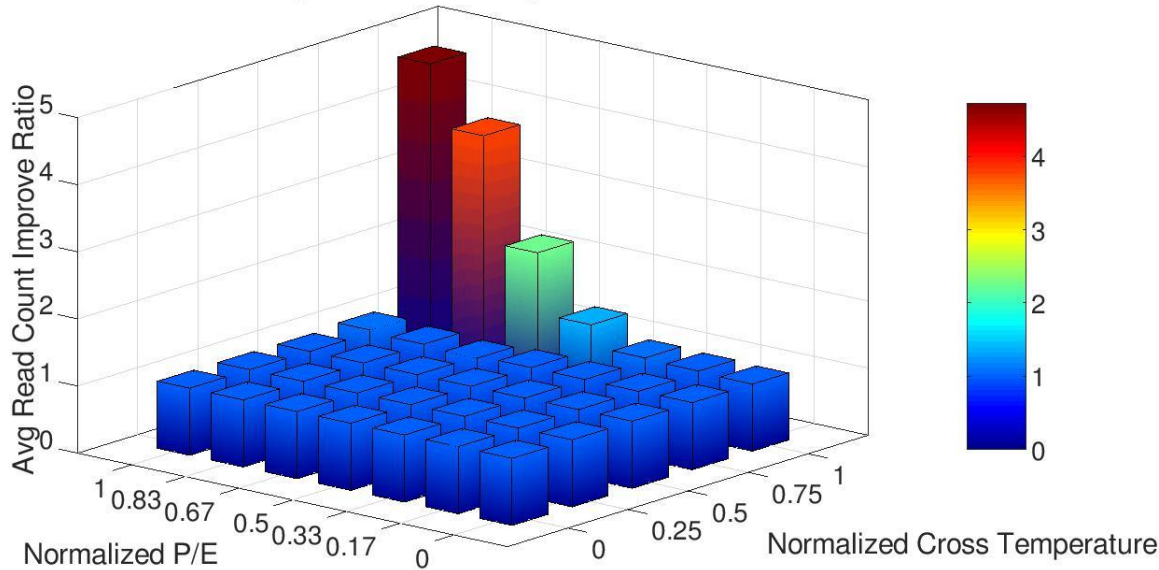
Cross Temperature - LT Write  
Avg Read Count - Comparison



- There is always a latency gap between cTLC and eTLC
- cTLC + ML can greatly reduce the read latency

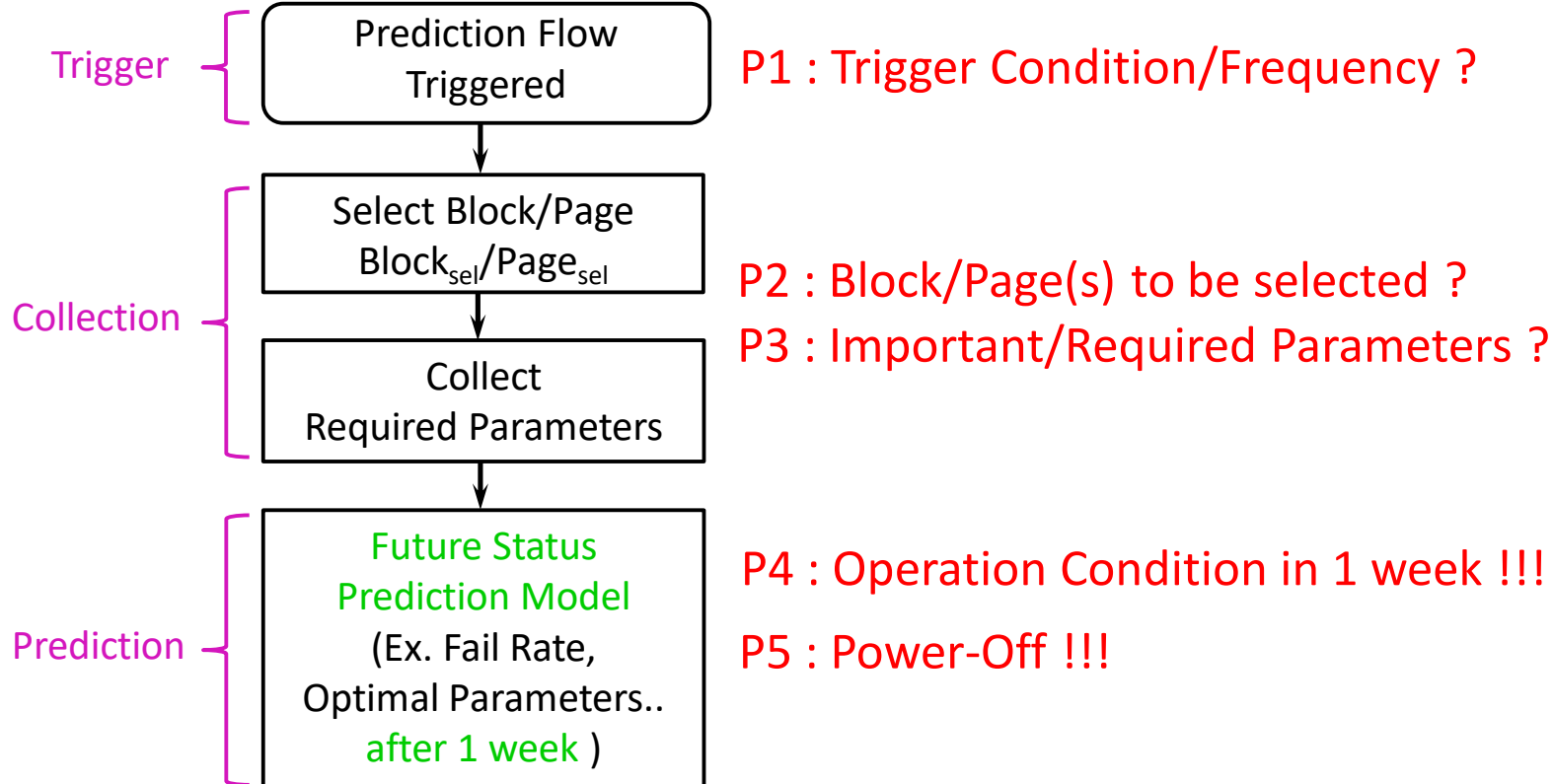
# cTLC vs eTLC – Latency – Cross Temp

Cross Temperature - LT Write  
Avg Read Count Improve Ratio



- Improvement Ratio :  $\text{Avg Read eTLC} / \text{Avg Read (cTLC + ML)}$
- cTLC + ML always has less read count compared with eTLC

# Implement For Future Status Prediction



# Summary

- **How to Extend Endurance & Reduce Error Recovery Latency**
  - Optimized Read Retry Sequence
  - Optimal Read Level, LLR, Status Prediction Model
  - Design Error Recovery Scheme based on NAND Flash Characteristic/Controller Architecture
- **Replace Enterprise Level TLC with Client Level TLC**
  - cTLC + ML can achieve eTLC specification (JESD218)
  - cTLC + ML can greatly reduce the latency compared with eTLC
  - Large sample testing follow JESD218 is on-going



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# THANK YOU!

## Any questions?

Come by LITE-ON **Booth# 621** for Demos!

- Learn about Machine Learning & the latest SSD Technology
  - Get a chance to win special prizes!

